

Absolute Maximum Ratings ${ }_{\text {(Note 1 }}$ 1)
Storage Temperature
Ambient Temperature under Bias Junction Temperature under Bias $\mathrm{V}_{\mathrm{CC}}$ Pin Potential to Ground Pin Input Voltage (Note 2)
Input Current (Note 2)
Voltage Applied to Output in HIGH State (with $\mathrm{V}_{\mathrm{CC}}=0 \mathrm{~V}$ )
Standard Output
3-STATE Output
Current Applied to Output
in LOW State (Max)
ESD Last Passing Voltage (Min)
twice the rated $\mathrm{I}_{\mathrm{OL}}(\mathrm{mA})$

## DC Electrical Characteristics

| Symbol | Parameter | Min | Typ | Max | Units | $\mathrm{V}_{\mathrm{cc}}$ | Conditions |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {T+ }}$ | Positive-Going Threshold | 1.5 | 1.7 | 2.0 | V | 5.0 V |  |
| $\mathrm{V}_{\text {T- }}$ | Negative-Going Threshold | 0.7 | 0.9 | 1.1 | V | 5.0 V |  |
| $\Delta \mathrm{V}_{\mathrm{T}}$ | Hysteresis ( $\mathrm{V}_{\mathrm{T}_{+}-\mathrm{V}_{T-} \text { ) }}$ | 0.4 | 0.8 |  | V | 5.0V |  |
| $\mathrm{V}_{\mathrm{CD}}$ | Input Clamp Diode Voltage |  |  | -1.2 | V | Min | $\mathrm{l}_{\mathrm{IN}}=-18 \mathrm{~mA}$ |
| $\mathrm{V}_{\mathrm{OH}}$ | Output HIGH $10 \% \mathrm{~V}_{\mathrm{CC}}$ <br> Voltage $5 \% \mathrm{~V}_{\mathrm{CC}}$ | $\begin{aligned} & 2.5 \\ & 2.7 \end{aligned}$ |  |  | V | Min | $\begin{aligned} & \mathrm{l}_{\mathrm{OH}}=-1 \mathrm{~mA} \\ & \mathrm{l}_{\mathrm{OH}}=-1 \mathrm{~mA} \end{aligned}$ |
| $\mathrm{V}_{\text {OL }}$ | Output LOW  <br> Voltage $10 \% V_{C C}$ |  |  | 0.5 | V | Min | $\mathrm{l} \mathrm{OL}=20 \mathrm{~mA}$ |
| $\overline{I_{\mathrm{H}}}$ | Input HIGH <br> Current |  |  | 5.0 | $\mu \mathrm{A}$ | Max | $\mathrm{V}_{\mathrm{IN}}=2.7 \mathrm{~V}$ |
| $\bar{l}_{\text {BVI }}$ | Input HIGH Current <br> Breakdown Test |  |  | 7.0 | $\mu \mathrm{A}$ | Max | $\mathrm{V}_{\mathrm{IN}}=7.0 \mathrm{~V}$ |
| ${ }_{\text {ICEX }}$ | Output HIGH <br> Leakage Current |  |  | 50 | $\mu \mathrm{A}$ | Max | $\mathrm{V}_{\text {OUT }}=\mathrm{V}_{\text {CC }}$ |
| $\mathrm{V}_{\text {ID }}$ | Input Leakage Test | 4.75 |  |  | V | Max | $\mathrm{I}_{\mathrm{ID}}=1.9 \mu \mathrm{~A}$ <br> All Other Pins Grounded |
| $\overline{\mathrm{IOD}}$ | Output Leakage Circuit Current |  |  | 3.75 | $\mu \mathrm{A}$ | 0.0 | $\mathrm{V}_{\text {IOD }}=150 \mathrm{mV}$ <br> All Other Pins Grounded |
| ILL | Input LOW Current |  |  | -0.6 | mA | Max | $\mathrm{V}_{\text {IN }}=0.5 \mathrm{~V}$ |
| Ios | Output Short-Circuit Current | -60 |  | -150 | mA | Max | $\mathrm{V}_{\text {OUT }}=0 \mathrm{~V}$ |
| $\mathrm{I}_{\text {CCH }}$ | Power Supply Current |  |  | 25 | mA | Max | $\mathrm{V}_{\mathrm{O}}=\mathrm{HIGH}$ |
| ${ }^{\text {CCL }}$ | Power Supply Current |  |  | 25 | mA | Max | $\mathrm{V}_{\mathrm{O}}=$ LOW |

## AC Electrical Characteristics

| Symbol | Parameter | $\begin{gathered} \mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C} \\ \mathrm{~V}_{\mathrm{CC}}=+5.0 \mathrm{~V} \\ \mathrm{C}_{\mathrm{L}}=50 \mathrm{pF} \end{gathered}$ |  | $\begin{gathered} \mathrm{T}_{\mathrm{A}}=-55^{\circ} \mathrm{C} \text { to }+125^{\circ} \mathrm{C} \\ \mathrm{~V}_{\mathrm{CC}}=+5.0 \mathrm{~V} \\ \mathrm{C}_{\mathrm{L}}=50 \mathrm{pF} \end{gathered}$ |  | $\begin{gathered} \mathrm{T}_{\mathrm{A}}=\mathbf{0}^{\circ} \mathrm{C} \text { to }+70^{\circ} \mathrm{C} \\ \mathrm{~V}_{\mathrm{CC}}=+5.0 \mathrm{~V} \\ \mathrm{C}_{\mathrm{L}}=50 \mathrm{pF} \end{gathered}$ |  | Units |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min | Max | Min | Max | Min | Max |  |
| $\begin{aligned} & \overline{\mathrm{t}_{\mathrm{PLH}}} \\ & \mathrm{t}_{\mathrm{PHL}} \end{aligned}$ | Propagation Delay $\mathrm{I}_{\mathrm{n}} \rightarrow \overline{\mathrm{O}}_{\mathrm{n}}$ | $\begin{aligned} & 4.0 \\ & 3.5 \end{aligned}$ | $\begin{gathered} 10.5 \\ 8.5 \end{gathered}$ | 4.0 3.5 | $\begin{aligned} & 13.0 \\ & 10.0 \end{aligned}$ | 4.0 3.5 | $\begin{gathered} \hline 11.5 \\ 9.0 \end{gathered}$ | ns |




Physical Dimensions inches (millimeters) unless otherwise noted (Continued)


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